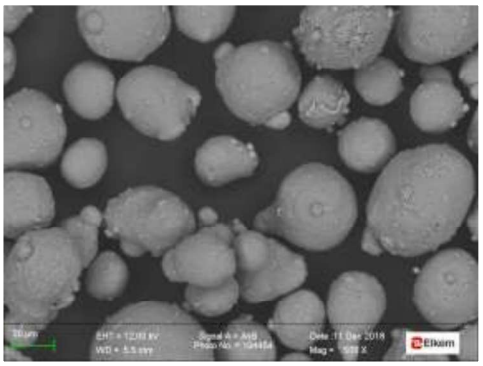
Scanning Electron Microscope
Examples

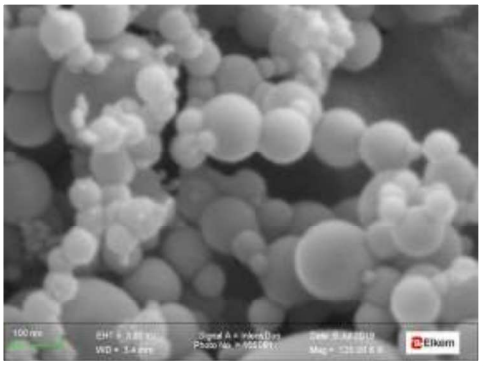
A Scanning Electron Microscope (SEM) is utilised in almost every material challenge, whether its development work, troubleshooting or documentation of microstructure and chemistry. Our SEM is an important tool in research and development and its possibilities are almost endless within materials characterisation.

EXAMPLES

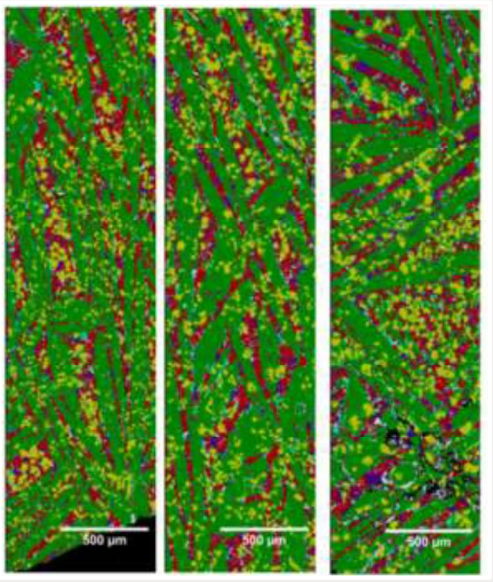


Studying size and morphology of gas atomised particles

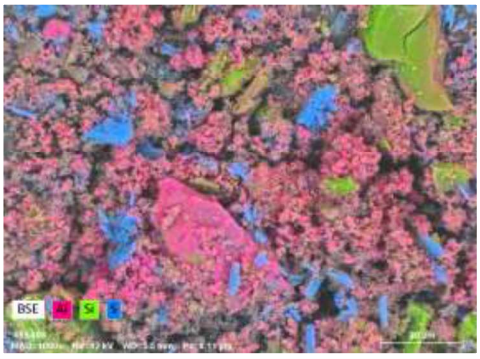
Examine growth of SiC (Carbide) and Si3N4 (Nitride) crystals on a substrate



Nano sized particles at 120 000X



AMICS. Large scale mapping of a Ferro Silicon Magnesium alloy (FSM)



Mapping of Aluminium, Silicon and Sulphur in a crushed mineral

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